

Notice of References Cited

Application/Control No.

10/031,545

Applicant(s)/Patent Under
Reexamination
MURATA ET AL.

Examiner

Edna Wong

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Art Unit

1753

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,414,213 B2	07-2002	Ohmori et al.	588/227
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 9411092 A1	05-1994	World Intellect	WATANABE et al.	B01D 53/36
*	O	JP 02280818 A	11-1990	Japan	IKEDA et al.	B01D 53/36
*	P	JP 0532039 U	04-1993	Japan		
*	Q	JP 10155887 A	06-1998	Japan	MOCHIKI, TADASHI	A61L 09/015
	R	JP 10249356 A	09-1998	Japan	ISHINO, YUICHI	C02F 01/50
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	* References N-Q were cited on the International Search Report.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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